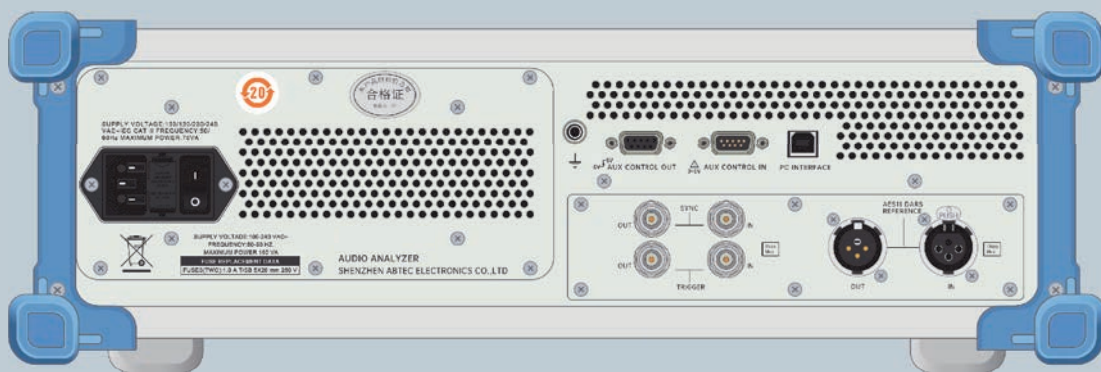


Audio Analyzer A10

High-performance and multifunctional
audio testing solution for laboratories



A10 is a 2-channel analog audio analyzer fully comparable to AP Company's APx555B. Equipped with a high-performance sine signal generator and analyzer, it can produce sine signals up to 204kHz, with a system residual THD+N (Total Harmonic Distortion plus Noise) of less than -120dB, a test bandwidth exceeding 1MHz, and supports all digital interfaces (ADIO/BT/I2S/HDMI/PDM/A2B) and the Advanced Master Clock (AMC) module. It is an ideal testing device for the R&D phase of audio products.



Call to Actions

More details <https://www.doewe.com> — 01

Performance Specifications

System Performance	
Residual THD+N (20kHz BW)	-117dB, Typical < -120dB(1kHz, 2.0V)

Signal Source Specifications	
Sine Wave Frequency Range	DAC: 0.001Hz-80kHz, Analog: 5Hz-204kHz
Frequency Accuracy	DAC: 3ppm Analog Precision Tune off: ±0.35%(10Hz-100kHz)
IMD Test Signals	SMPTE, MOD, DFD, DIM
Maximum Output Amplitude (Balanced)	26.66Vrms
Amplitude Accuracy (1kHz)	±0.03dB
Amplitude Flatness (5Hz-20kHz)	±0.008dB
Analog Output Configuration	Balanced & Unbalanced & Common Mode
ADC Test Bias Voltage	-0.4-4.2VDC
Maximum Digital Output Sampling Rate	216kHz
Sampling Accuracy	3ppm
Bit Depth	8-24bit
Dolby/dts Signal Source	Yes (pre-encoded files)

Analyzer Specifications	
Max Rated Input Voltage	300Vrms
Max Bandwidth	1MHz
IMD Test Capability	SMPTE, MOD, DFD, DIM
Amplitude Accuracy (1 kHz)	±0.03dB
Amplitude Flatness (10 Hz - 20 kHz)	±0.008dB
Residual Input Noise (22 kHz BW)	1.0µV
Independent Harmonic Analysis	d2-d10
Max FFT Length	1.2M points
DC Voltage Measurement	

General Specifications

Dimensions (W×D×H)	480mm*522mm*153mm
Weight	9.5kg±0.5kg
Operating Voltage (AC)	220V, 50Hz/100V-240V, 50Hz-60Hz

Key Features

Fully benchmarked against the AP APx555B audio analyzer

Codeless automation and comprehensive API interface

Supports digital interface expansion including BT/HDMI/I2S/PDM/A2B

Supports LabVIEW, VB.NET, C#.NET, Python

Standard support for SPDIF/TOSLINK/AES/EBU digital interfaces; capable of generating advanced alarm signals

Standard support for Advanced Master Clock (AMC) module, used for synchronization and jitter signal generation/analysis

Supports Dolby & DTS digital stream playback

Multi-mode user interface, supporting Sequence and Workbench modes

Universal software platform generates reports and images in multiple formats for easy sharing

Tailored for amplifier designers: Automatically measures Continuous Max Output, Peak Max Output, DIM, CMRR, etc

Options

Bluetooth R&D Interface Option	AB-BT-DUO
PDM Interface Option	AB-PDM/PDM16
DSIO Interface Option	AB-DSIO
HDMI Interface Option	AB-HDMI2+eARC
Audio Bus Interface	AB-A2B
Perceptual Audio Test Option	AX-PESQ/POLQA2
Speech Transmission Test Option	AX-STIPA

A10-ADC TEST Option

To validate and test complex multi-channel Analog-to-Digital Converters (ADCs), the A10 offers an ADC Test Mode option. This mode generates balanced analog audio signals combined with a calibrated common-mode DC offset voltage. This functionality is particularly useful for testing devices powered by single-supply voltages and requiring DC-biased inputs, such as audio codecs and ADC chips in mobile products. The ADC Test Mode also includes programmable voltage limits to prevent overvoltage damage to the Device Under Test (DUT)





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